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F-7094

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Toru MATSUMOTO et al.
Serial No. : (Not yet known)
Filed : (Concurrently herewith)
For : SEMICONDUCTOR TEMPERATURE
DETECTING METHOD AND ITS CIRCUIT
Group Art Unit : (Not yet known)
Examiner : (Not yet known)

Assistant Commissioner
for Patents
Washington, D.C. 20231

PRELIMINARY AMENDMENT (A)

Sir:

Preliminary to examination, please amend the above-identified patent application as follows:

IN THE CLAIMS:

Please amend the claim as shown rewritten below with amendments effected therein. Appendix I is attached hereto having marked versions of said claim with amendments indicated by brackets and underlining.

RECEIVED - 07/13/12